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Microbeam analysis - Guidelines for orientation measurement using electron backscatter diffraction (ISO 24713:2009)

Contents

Page

National foreword ... 4

National Annex NA (informative) Bibliography ... 4

Introduction ... 5

1 Scope ... 6

2 Normative references ... 6

3 Terms and definitions ... 6

4 Equipment for EBSD ... 12

5 Operating conditions ... 13
5.1 Specimen preparation ... 13
5.2 Specimen alignment ... 14
5.3 Common steps in collecting an EBSP ... 14
5.3.1 Setting the microscope operating conditions ... 14
5.3.2 Detector and working distances ... 14
5.3.3 Camera integration/exposure time ... 15
5.3.4 Binning ... 15
5.3.5 EBSP averaging ... 16
5.3.6 EBSP background correction/EBSP signal correction ... 16
5.3.7 Band detection ... 17

6 Calibrations required for indexing of EBSPs ... 18

7 Analytical procedure ... 21
7.1 Pre-test preparation ... 21
7.2 Operating conditions ... 22
7.3 Equipment stability check ... 22
7.4 EBSD analysis ... 22

8 Measurement uncertainty ... 22
8.1 General ... 22
8.2 Uncertainty of crystal orientation measurement ... 22
8.3 Absolute orientation ... 23
8.4 Relative orientation ... 23

9 Reporting the results ... 23

Annex A (informative) Principle of EBSD ... 24

Annex B (normative) Specimen preparation for EBSD ... 25

B.1 General ... 25
B.2 Cutting ... 25
B.3 Mounting ... 25
B.4 Grinding ... 25
B.5 Polishing ... 26

B.6 Etching ... 27
B.7 Ion beam techniques ... 28
B.8 Conductive coating [22] ... 30

Annex C (informative) Brief introduction to crystallography and EBSP indexing, and other information useful for EBSD ... 31

C.1 General ... 31
C.2 Symmetry ... 31
C.3 The unit cell ... 32
C.4 Crystal directions ... 32
C.5 Crystal planes ... 33
C.6 Crystal systems ... 33
C.7 Laue groups ... 34
C.8 Bravais lattices ... 35
C.9 Manual indexing of a cubic EBSP ... 36
C.10 Examples of indexed cubic EBSPs ... 37
C.11 Hexagonal indices ... 38
C.12 Useful formulae and information ... 40
C.12.1 Symbols ... 40
C.12.2 Electron wavelength as a function of accelerating voltage ... 41
C.12.3 Interplanar spacing for plane (hkl) ... 41
C.12.4 Unit cell volume ... 41
C.12.5 Angle between two planes (h1k1l1) and (h2k2l2) ... 42
C.12.6 To find the zone [uvw] that is perpendicular to plane (hkl) ... 42
C.12.7 Relationships between zones and planes ... 42
C.12.8 Conditions for a Kikuchi band to be visible ... 42
C.12.9 Cubic interzonal and interplanar angles ... 44
C.12.10 Cristallographic information for selected cubic phases ... 45
C.12.11 Cristallographic information for selected hexagonal, tetragonal and orthorhombic phases ... 45
C.12.12 Cubic coincidence site lattice (CSL) misorientation relationships ... 46

Bibliography ... 47